

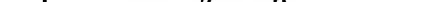
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PTO/SB/08A (08-00)

<p>Substitute for form 1, 65A/PTO  INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i></p>				<p><i>Complete if Known</i></p>	
<p>Application Number</p>		<p>09/844,673</p>			
<p>Filing Date</p>		<p>April 30, 2001</p>			
<p>First Named Inventor</p>		<p>THEKKATH</p>			
<p>Group Art Unit</p>		<p>2483 2122</p>			
<p>Examiner Name</p>		<p>Unassigned RUTTEN</p>			
<p>Sheet</p>		<p>1 of 2</p>		<p>Attorney Docket Number</p>	
				<p>MTEC-006/00US (0123.00US)</p>	

U.S. PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS

Examiner Signature		Date Considered	12/22/04
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Unique citation designation number.

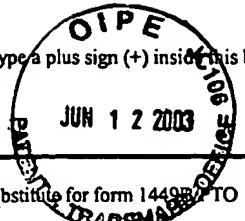
² See attached Kinds of U.S. Patent Documents.

³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3).

⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document.

5. Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible.

⁶ Applicant is to place a check mark here if English language Translation is attached.



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JUN 12 2003

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<p>Substitute for form 1449B/TO TRADEMARKS</p> <p>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</p> <p><i>(use as many sheets as necessary)</i></p>				<p><i>Complete if Known</i></p>		
<p>Sheet</p>		<p>2</p>	<p>of</p>	<p>2</p>	<p>Attorney Docket Number</p>	<p>MTEC-006/00US (0123.00US)</p>
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<p>First Named Inventor</p>		<p>THEKKATH</p>				
<p>Group Art Unit</p>		<p>2183</p>				
<p>Examiner Name</p>		<p>Unassigned</p>				

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

Examiner Signature		Date Considered	12/22/04
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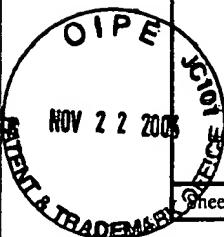
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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(use as many sheets as necessary)

Sheet

1 of 2

Complete if Known

Application Number	09/844,673
Filing Date	April 30, 2001
First Named Inventor	THEKKATH
Group Art Unit	2103 2122
Examiner Name	Gross, Kenneth A. RUTTEN
Attorney Docket Number	MTEC-006/00US

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY
		Number	Kind Code ² (if known)		
JDR	P1	3,473,154		Couleur et al.	10/14/1969
JDR	P2	3,585,599		Hitt	06/15/1971
JDR	P3	3,681,534		Burian et al.	08/01/1972
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	P36	5,748,904		Huang et al.	05/05/1998
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<i>JDR</i>	P45	6,282,701		Wygodny et al.	08/28/2001
	P46	6,338,159		Alexander	01/08/2002
	P47	6,353,924		Ayers et al.	03/05/2002
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	P50	6,487,715		Chamdani et al.	11/26/2002
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FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	T ⁴
		Office ¹	Number ²	Kind Code ³ (if known)			
<i>JDR</i>	F1	GB	2 329 048		ARM Limited	10/03/1999	
<i>JDR</i>	F2	GB	2 329 049		ARM Limited	10/03/1999	

Examiner Signature		Date Considered	12/21/04
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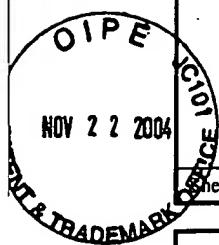
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Sheet	1	of	1	First Named Inventor
				THEKKATH
			Group Art Unit	2183
			Examiner Name	Gross, Kenneth A.
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OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS				
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.		
SDR	1	Embedded Trace Macrocell Specification, Rev. 0/0a, ARM IHI 0014C, ARM Ltd. (1999) <i>Odd-Numbered pages only</i>		
Examiner Signature				Date Considered
				12/21/04

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